



PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Florida Calibration Lab
3408 W. 84 #109, Hialeah, FL 33018

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2005

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Dimensional, Electrical, Mass, Force & Weighing Devices Calibration
(As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen
President/Operations Manager

Initial Accreditation Date:

January 24, 2014

Issue Date:

August 2, 2018

Expiration Date:

September 30, 2020

Accreditation No.:

78127

Certificate No.:

L18-367

Perry Johnson Laboratory
Accreditation, Inc. (PJLA)
755 W. Big Beaver, Suite 1325
Troy, Michigan 48084

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pjllabs.com



Certificate of Accreditation: Supplement

Florida Calibration Lab

3408 W 84 Street # 109, Hialeah, FL. 33018
 Contact Name: Yami Sanchez Phone: 305-421-7212

Accreditation is granted to the facility to perform the following calibrations:

Dimensional

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Calipers ^F	0.05 in to 24 in	(315 + 7.9L) μ m	Gage Blocks Long Gage Blocks
Inside Micrometers ^F	1.5 in to 12 in	(13.8 + 12L) μ m	
Outside Micrometers ^F	0.05 in to 12 in	(30 + 4L) μ m	
Dial Indicator ^F	0.001 to 2 in	(360 + 18L) μ m	
Depth Micrometer ^F	0.05 in to 12 in	(51.2 + 6L) μ m	

Electrical

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED	
Equipment to Measure DC Voltage ^F	1 mV to 320 mV	0.001 8 % of Reading + 0.058 mV	Wavetek 9100	
	0.32 V to 3.2 V	0.001 9 % of Reading + 580 μ V		
	3.2 V to 32 V	0.002 2 % of Reading + 5.8 mV		
	32 V to 320 V	0.002 3 % of Reading + 58 mV		
	320 V to 1 050 V	0.000 82 % of Reading + 580 mV		
Equipment to Measure DC Current ^F	0.001 μ A to 320 μ A	0.008 6 % of Reading + 59 nA		
	0.32 mA to 3.2 mA	0.001 1 % of Reading + 5.8 μ A		
	3.2 mA to 32 mA	0.008 7 % of Reading + 5.8 μ A		
	32 mA to 320 mA	0.025 % of Reading + 10 μ A		
	0.32 A to 3.2 A	0.069 % of Reading + 140 μ A		
	3.2 A to 10.5 A	0.043 % of Reading + 5.2 mA		
Equipment to Measure AC Voltage (At the listed frequencies) ^F	10.5 A to 20 A	0.016 % of Reading + 57 mA		
	10 Hz to 3 kHz	0.001 mV to 10 mV		0.046 % of Reading + 450 μ V
	3 kHz to 10 kHz	0.001 mV to 10 mV		0.046 % of Reading + 600 μ V
	10 kHz to 30 kHz	0.001 mV to 10 mV		0.069 % of Reading + 1 100 μ V
	30 kHz to 50 kHz	0.001 mV to 10 mV	0.1 % of Reading + 2.2 mV	
	50 kHz to 100 kHz	0.001 mV to 10 mV	0.23 % of Reading + 5.9 mV	



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Equipment to Measure AC Voltage (At the listed frequencies) ^F			Wavetek 9100
10 Hz to 3 kHz	10 mV to 32 mV	0.044 % of Reading + 160 μ V	
3 kHz to 10 kHz	10 mV to 32 mV	0.068 % of Reading + 280 μ V	
10 kHz to 30 kHz	10 mV to 32 mV	0.042 % of Reading + 130 μ V	
30 kHz to 50 kHz	10 mV to 32 mV	0.1 % of Reading + 560 μ V	
50 kHz to 100 kHz	10 mV to 32 mV	0.23 % of Reading + 1.5 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	32 mV to 320 mV	0.039 % of Reading + 56 μ V	
3 kHz to 10 kHz	32 mV to 320 mV	0.04 % of Reading + 60 μ V	
10 kHz to 30 kHz	32 mV to 320 mV	0.065 % of Reading + 76 μ V	
30 kHz to 50 kHz	32 mV to 320 mV	0.1 % of Reading + 120 μ V	
50 kHz to 100 kHz	32 mV to 320 mV	0.23 % of Reading + 300 μ V	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	0.32 V to 3.2 V	0.049 % of Reading + 220 μ V	
3 kHz to 10 kHz	0.32 V to 3.2 V	0.049 % of Reading + 290 μ V	
10 kHz to 30 kHz	0.32 V to 3.2 V	0.071 % of Reading + 550 μ V	
30 kHz to 50 kHz	0.32 V to 3.2 V	0.11 % of Reading + 1 100 μ V	
50 kHz to 100 kHz	0.32 V to 3.2 V	0.23 % of Reading + 3 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	3.2 V to 32 V	0.049 % of Reading + 2.2 mV	
3 kHz to 10 kHz	3.2 V to 32 V	0.072 % of Reading + 2.9 mV	
10 kHz to 30 kHz	3.2 V to 32 V	0.094 % of Reading + 5.5 mV	
30 kHz to 50 kHz	3.2 V to 32 V	0.17 % of Reading + 11 mV	
50 kHz to 100 kHz	3.2 V to 32 V	0.41 % of Reading + 37 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	32 V to 105 V	0.078 % of Reading + 0.16 mV	
3 kHz to 10 kHz	32 V to 105 V	0.094 % of Reading + 2.6 mV	
10 kHz to 30 kHz	32 V to 105 V	0.11 % of Reading + 13 mV	
30 kHz to 50 kHz	32 V to 105 V	0.18 % of Reading + 33 mV	
50 kHz to 100 kHz	32 V to 105 V	0.41 % of Reading + 120 mV	



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Equipment to Measure AC Voltage (At the listed frequencies) ^F			Wavetek 9100
40 Hz to 100 Hz	105 V to 320 V	0.053 % of Reading + 45 mV	
100 Hz to 1 kHz	105 V to 320 V	0.053 % of Reading + 45 mV	
1 kHz to 3 kHz	105 V to 320 V	0.089 % of Reading + 39 mV	
3 kHz to 10 kHz	105 V to 320 V	0.089 % of Reading + 52 mV	
10 kHz to 20 kHz	105 V to 320 V	0.14 % of Reading + 66 mV	
20 kHz to 30 kHz	105 V to 320 V	0.17 % of Reading + 82 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
40 Hz to 100 Hz	320 V to 800 V	0.057 % of Reading + 83 mV	
100 Hz to 1 kHz	320 V to 800 V	0.073 % of Reading + 82 mV	
1 kHz to 3 kHz	320 V to 800 V	0.092 % of Reading + 85 mV	
3 kHz to 10 kHz	320 V to 800 V	0.092 % of Reading + 130 mV	
10 kHz to 20 kHz	320 V to 800 V	0.14 % of Reading + 190 mV	
20 kHz to 30 kHz	320 V to 800 V	0.17 % of Reading + 250 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
40 Hz to 100 Hz	800 V to 1 050 V	0.044 % of Reading + 490 mV	
100 Hz to 1 kHz	800 V to 1 050 V	0.044 % of Reading + 490 mV	
1 kHz to 3 kHz	800 V to 1 050 V	0.08 % of Reading + 420 mV	
3 kHz to 10 kHz	800 V to 1 050 V	0.082 % of Reading + 490 mV	
10 kHz to 20 kHz	800 V to 1 050 V	0.13 % of Reading + 540 mV	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	0.001 μ A to 32 μ A	0.081 % of Reading + 1 000 nA	
3 kHz to 10 kHz	0.001 μ A to 32 μ A	0.12 % of Reading + 2.1 μ A	
10 kHz to 20 kHz	0.001 μ A to 32 μ A	0.23 % of Reading + 6.9 μ A	
20 kHz to 30 kHz	0.001 μ A to 32 μ A	0.29 % of Reading + 10.43 μ A	
Equipment to Measure AC Voltage (At the listed frequencies) ^F			
10 Hz to 3 kHz	32 μ A to 320 μ A	0.08 % of Reading + 350 nA	
3 kHz to 10 kHz	32 μ A to 320 μ A	0.12 % of Reading + 700 nA	
10 kHz to 20 kHz	32 μ A to 320 μ A	0.23 % of Reading + 2.3 μ A	
20 kHz to 30 kHz	32 μ A to 320 μ A	0.29 % of Reading + 3.5 μ A	



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Equipment to Measure AC current (At the listed frequencies) ^F			Wavetek 9100
10 Hz to 3 kHz	0.32 mA to 3.2 mA	0.023 % of Reading + 5.7 μ A	
3 kHz to 10 kHz	0.32 mA to 3.2 mA	0.048 % of Reading + 5.7 μ A	
10 kHz to 20 kHz	0.32 mA to 3.2 mA	0.17 % of Reading + 6 μ A	
20 kHz to 30 kHz	0.32 mA to 3.2 mA	0.23 % of Reading + 6.5 μ A	
Equipment to Measure AC current (At the listed frequencies) ^F			
10 Hz to 3 kHz	3.2 mA to 32 mA	0.075 % of Reading + 6.1 μ A	
3 kHz to 10 kHz	3.2 mA to 32 mA	0.11 % of Reading + 8.9 μ A	
10 kHz to 20 kHz	3.2 mA to 32 mA	0.23 % of Reading + 16 μ A	
20 kHz to 30 kHz	3.2 mA to 32 mA	0.29 % of Reading + 26 μ A	
Equipment to Measure AC current (At the listed frequencies) ^F			
10 Hz to 3 kHz	32 mA to 320 mA	0.094 % of Reading + 37 μ A	
3 kHz to 10 kHz	32 mA to 320 mA	0.12 % of Reading + 55 μ A	
10 kHz to 20 kHz	32 mA to 320 mA	0.23 % of Reading + 74 μ A	
20 kHz to 30 kHz	32 mA to 320 mA	0.29 % of Reading + 110 μ A	
Equipment to Measure AC current (At the listed frequencies) ^F			
10 Hz to 3 kHz	0.32 A to 3.2 A	0.22 % of Reading + 230 μ A	
3 kHz to 10 kHz	0.32 A to 3.2 A	0.22 % of Reading + 6.5 mA	
Equipment to Measure AC current (At the listed frequencies) ^F			
10 Hz to 3 kHz	3.2 A to 10.5 A	0.22 % of Reading + 5.3 mA	
3 kHz to 10 kHz	3.2 A to 10.5 A	0.57 % of Reading + 12 mA	
Equipment to Measure AC current (At the listed frequencies) ^F			
10 Hz to 3 kHz	10.5 A to 20 A	0.23 % of Reading + 8.7 mA	
3 kHz to 10 kHz	10.5 A to 20 A	0.58 % of Reading + 27 mA	



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Equipment to Measure Capacitance ^F	0.5 nF to 4 nF	0.34 % of Reading + 0.18 nF	Wavetek 9100
	4 nF to 40 nF	0.37 % of Reading + 0.034 nF	
	40 nF to 400 nF	0.37 % of Reading + 0.18 nF	
	400 nF to 4 μ F	0.46 % of Reading + 1.9 nF	
	4 μ F to 40 μ F	0.58 % of Reading + 19 nF	
	40 nF to 400 μ F	0.52 % of Reading + 510 nF	
	400 μ F to 4mF	0.58 % of Reading + 1.9 μ F	
	4 mF to 40mF	1.2 % of Reading + 0.07 mF	
Equipment to Measure Frequency ^F	0.5 Hz to 10 MHz	0.003 % of Reading + 0.01 Hz	
Equipment to Measure Resistance ^F	0 Ω to 40 Ω	0.12 % of Reading + 45 m Ω	
	40 Ω to 400 Ω	0.1 % of Reading + 98 m Ω	
	0.4 k Ω to 4 k Ω	0.077 % of Reading + 401 m Ω	
	4 k Ω to 40 k Ω	0.1 % of Reading + 4 000 m Ω	
	40 k Ω to 400 Ω	0.09 % of Reading + 40 Ω	
	0.4 M Ω to 4 M Ω	0.011 % of Reading + 498 Ω	
	4 M Ω to 40 M Ω	0.25 % of Reading + 10 k Ω	
	4 M Ω to 400 M Ω	0.3 % of Reading + 200 k Ω	
Equipment to Output DC Voltage ^F	100 mV	0.034 mV	Agilent 34401A
	1 V	0.027 mV	
	10 V	1.2 mV	
	100 V	17 mV	
	1 000 V	0.22 V	
Equipment to Output AC Voltage (At the listed frequencies) ^F			
3 Hz to 5 Hz	100 mV	1.7 mV	
5 Hz to 10 Hz	100 mV	0.78 mV	
10 Hz to 20 kHz	100 mV	0.2 mV	
20 kHz to 50 kHz	100 mV	0.28 mV	
50 kHz to 100 kHz	100 mV	1.4 mV	
100 kHz to 300 kHz	100 mV	9 mV	



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Equipment to Output AC Voltage (At the listed frequencies) ^F			Agilent 34401A
3 Hz to 5 Hz	1 V to 750 V	0.6 % of Reading + 0.45 V	
5 Hz to 10 Hz	1 V to 750 V	0.7 % of Reading + 0.45 V	
10 Hz to 20 kHz	1 V to 750 V	0.12 % of Reading + 0.45 V	
20 kHz to 50 kHz	1 V to 750 V	0.18 % of Reading + 0.6 V	
50 kHz to 100 kHz	1 V to 750 V	1.2% of Reading + 1.2 V	
100 kHz to 300 kHz	1 V to 750 V	8 % of Reading + 7.5 V	
Equipment to Output Resistance ^F			
	100 Ω	0.023 Ω	
	1 k Ω	0.17 Ω	
	10 k Ω	1.7 Ω	
	100 k Ω	17 Ω	
	1 M Ω	0.17 k Ω	
	10 M Ω	6.2 k Ω	
	100 M Ω	1.2 M Ω	
Equipment to Output DC Current ^F			
	10 mA	0.003 6 mA	
	100 mA	0.066 mA	
	1 A	0.001 3 A	
	3 A	0.005 A	
Equipment to Output AC Voltage (At the listed frequencies) ^F			
3 Hz to 5 Hz	0.001 A to 1 A	1 % of Reading + 0.000 4 A	
5 Hz to 10 Hz	0.001 A to 1 A	0.3 % of Reading + 0.000 4 A	
10 Hz to 5 kHz	0.001 A to 1 A	0.1 % of Reading + 0.000 4 A	
Equipment to Output AC Voltage (At the listed frequencies) ^F			
3 Hz to 5 Hz	1 A to 3 A	1.1 % of Reading + 0.001 8 A	
5 Hz to 10 Hz	1 A to 3 A	0.35 % of Reading + 0.001 8 A	
10 Hz to 5 kHz	1 A to 3 A	0.15 % of Reading + 0.001 8 A	
Equipment to Measure Frequency (At the listed voltages) ^F			
3 Hz to 5 Hz	100 mV to 750 V	0.15 % of Reading	
5 Hz to 10 Hz	100 mV to 750 V	0.1 % of Reading	
10 Hz to 40 Hz	100 mV to 750 V	0.1 % of Reading	
40 Hz to 300 kHz	100 mV to 750 V	0.05 % of Reading	



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Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type J ^F	-210 °C to 1 200 °C	0.5 °C	Electrical Simulation of Thermocouple Output Wavetek 9100. With Cold Junction
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type K ^F	-250 °C to 1 372 °C	0.5 °C	
Temperature Calibration, Indication, and Control Equipment used Thermocouple Type T ^F	-250 °C to 400 °C	0.5 °C	
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type B ^F	500 °C to 1 820 °C	0.6 °C	
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type E ^F	-250 °C to 1 000 °C	0.5 °C	
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type C ^F	0 °C to 2 320 °C	0.6 °C	
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type N ^F	-200 °C to 1 300 °C	0.6 °C	Electrical Simulation of Thermocouple Output Wavetek 9100
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type R ^F	0 °C to 1 767 °C	0.6 °C	
Temperature Calibration, Indication, and Control Equipment used with Thermocouple Type S ^F	0 °C to 1 767 °C	0.7 °C	



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Mass, Force, and Weighing Devices

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Scale Class I ^{FO} (OIML)	0.001 g to 200 g	$(1.94 \times 10^{-5} Wt + 2.98 \times 10^{-2})$ g	Class F1 (OIML)
Scale class II ^{FO} (OIML)	0.003 kg to 10 kg	$(2.46 \times 10^{-6} Wt + 8 \times 10^{-5})$ g	
Scale class III ^{FO} (OIML)	0.001 kg to 10 kg	$(9.8 \times 10^{-6} Wt + 8.8 \times 10^{-2})$ g	

1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor *k* (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
3. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer^F would mean that the laboratory performs this calibration at its fixed location.
4. The presence of a superscript FO means that the laboratory performs calibration of the indicated parameter both at its fixed location and onsite at customer locations. Example: Outside Micrometer^{FO} would mean that the laboratory performs this calibration at its fixed location and onsite at customer locations.
5. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location.
6. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.
7. The term Wt represents weight in pounds or grams (including SI multiple and submultiple units) appropriate to the uncertainty statement.